Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	177380	(determin$5 or detect$5 or measur$5 or calculat$5 or monitor$5 or inspect$5 or identify$5 or evaluat$5 or checking) near4 (defect or scrat$3 or particle)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:04
L2	23974	microscope and marker	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 12:38
L3	2861	1 and 2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 12:37
L4	25473	((determin$5 or detect$5 or measur$5 or calculat$5 or monitor$5 or inspect$5 or identify$5 or evaluat$5 or checking) near4 (defect or scrat$3 or particle)) near9 (surface or substrate)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:05
L5	91	microscope and (defect$5 near3 marker)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:13
L6	5	4 and 5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 12:38
L7	30	1 and 5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 12:48
L8	40	(defect$5 near3 marker) and (ink near3 (marker or marking))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:01

L9	9	4 and 8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:02
L10	222	((determin$5 or detect$5 or measur$5 or calculat$5 or monitor$5 or inspect$5 or identify$5 or evaluat$5 or checking) near4 (defect or scrat$3 or particle)) near9 ((lcd or (liquid near3 crystal near3 display$5)) near4 (surface or substrate))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:14
L11	2	10 and 5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:12
L12	59	lens and (defect$5 near3 marker)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:29
L13	2	10 and 12	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:13
L14	2	10 and 8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:13
L15	2	10 and (defect$5 near3 marker)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:14
L16	362	((determin$5 or detect$5 or measur$5 or calculat$5 or monitor$5 or inspect$5 or identify$5 or evaluat$5 or checking) near4 (defect or scrat$3 or particle)) near9 ((lcd or (liquid near3 crystal)) near4 (surface or substrate))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:30

L17	2	16 and (defect$5 near3 marker)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:15
L18	2	16 and 8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:16
L19	1702	(objective near2 lens) and marker	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:30
L20	2	16 and 19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:30
L21	264	1 and 19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:30
L22	2	(objective near2 lens) and ((defect$5 near3 marker) and (ink near3 (marker or marking)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:32
L23	3806	356/237.$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:32
L24	1161	356/239.$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:32

L25	4859	23 or 24	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:32
L26	8	25 and (defect$5 near3 marker)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:33